

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination CHUNG ET AL.	
			Examiner HUY T. NGUYEN	Art Unit 2621	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0012558	01-2003	Kim et al.	386/97
*	B	US-2001/0029500	10-2001	Tanaka, Masahide	707/3
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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